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# Extending X-Ray Crystallography to Allow the Imaging of Noncrystalline Materials, Cells, and Single Protein Complexes

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## Key Words

X-ray diffraction microscopy, oversampling method, lensless imaging, phase retrieval, noncrystalline specimen, single-molecule imaging, X-ray free electron lasers

## Abstract

In 1999, researchers extended X-ray crystallography to allow the imaging of noncrystalline specimens by measuring the X-ray diffraction pattern of a noncrystalline specimen and then directly phasing it using the oversampling method with iterative algorithms. Since then, the field has evolved moving in three important directions. The first is the 3D structural determination of noncrystalline materials, which includes the localization of the defects and strain field inside nanocrystals, and quantitative 3D imaging of disordered materials such as nanoparticles and biomaterials. The second is the 3D imaging of frozen-hydrated whole cells at a resolution of 10 nm or better. A main thrust is to localize specific multiprotein complexes inside cells. The third is the potential of imaging single large protein complexes using extremely intense and ultrashort X-ray pulses. In this article, we review the principles of this methodology, summarize recent developments in each of the three directions, and illustrate a few examples.

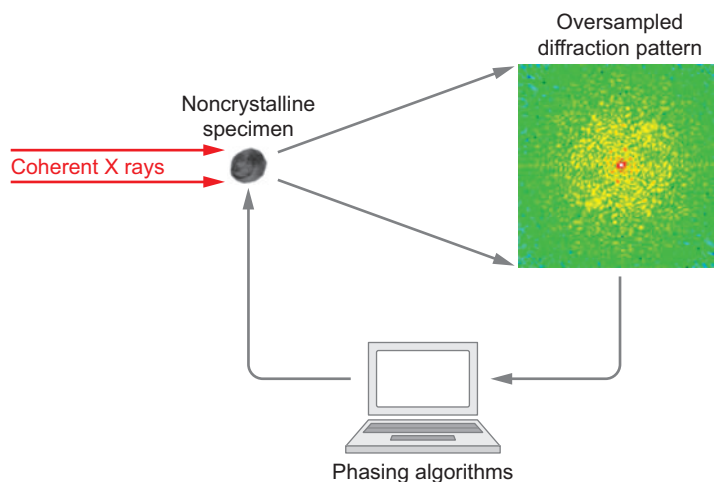
## INTRODUCTION

Von Laue's discovery of X-ray diffraction from crystals nearly 100 years ago marked the beginning of a new era for visualizing 3D atomic structures inside crystals. Indeed, X-ray crystallography has since made a tremendous impact in physics, chemistry, materials sciences, biology, and other areas. It has now reached a point at which it can determine almost any structure, as long as good-quality crystals are obtained. Many samples, however, cannot be accessed by this approach, such as amorphous and disordered materials including glasses, polymers, strains and defects in crystals, quantum dots and wires, dislocation and deformation structures, and some inorganic nanostructures. In biology, structures such as whole cells, organelles, viruses, and many important protein molecules cannot or are difficult to crystallize; hence their structures are not accessible by X-ray crystallography. Overcoming these limitations requires the employment of different techniques and methods, such as nuclear magnetic resonance spectroscopy (1) and cryo-electron microscopy (2, 3). One promising approach currently under rapid development is extending the methodology of X-ray crystallography to allow the structural determination of noncrystalline specimens, which we call X-ray diffraction microscopy (or lensless imaging) (4, 5). **Figure 1** shows the principles of X-ray diffraction microscopy. When a coherent wave of X rays illuminates a noncrystalline specimen, the far-field diffraction intensities are continuous and weak. The continuous intensities can be sampled at an arbitrary frequency (6). When the sample frequency is sufficiently finer than the Nyquist interval (i.e., the inverse of the sample size) so that the number of independent intensity points is more than the number of unknown variables, the phases are encoded in the intensities (7) and can be retrieved directly using an iterative algorithm (8–11). Here the number of unknown variables represents the voxel number of an array sampling the sample structure.

Historically, Sayre (12, 13) first suggested the idea of X-ray diffraction microscopy. It was not until in 1999 that Miao et al. (14) carried out the first experimental

**Figure 1**

The principles of X-ray diffraction microscopy.



demonstration. Since then, over 20 groups worldwide have applied the technique successfully to imaging a variety of samples, ranging from nanoparticles, nanocrystals, and biomaterials to whole cells (15–39). A biennial international workshop series has been organized to discuss current progress and the future potential of this emerging field (40). In this article, we review the principles of the oversampling method with iterative algorithms and illustrate a few applications of X-ray diffraction microscopy to imaging noncrystalline materials and biological cells. Finally, we discuss the potential of imaging single large protein complexes using extremely intense and ultrafast X-ray free electron laser (XFEL) pulses.

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**XFEL:** X-ray free electron laser

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## THE OVERSAMPLING METHOD AND ITERATIVE ALGORITHMS

### The Phase Problem

A typical X-ray diffraction experiment involves measuring a series of far-field diffraction patterns from the specimen and inverting the diffraction patterns to reconstruct the specimen structure. In principle, the intensity of each diffraction pattern depends on the exact arrangement of atom positions in the specimen, and by quantitatively analyzing all intensities, one can retrieve the exact locations of all atoms in the structure. Unfortunately, this is not as easy as one would think because the measured intensity pattern is only directly related to the modulus of a Fourier transform of the specimen's electron density, and the phase information is not easily available. To reconstruct the electron density, one needs both the magnitudes and the phases, as in any inverse Fourier transform for reconstruction. This loss of phase information is the fundamental phase problem in diffraction measurements and can be classified into a greater category of inversion problems that exist in all wave-field propagation measurements in optics and other related fields (41, 42).

Ever since the discovery of X-ray diffraction from crystals in the early twentieth century, efforts to seek solutions to the phase problem have been central to work in X-ray crystallography. Scientists solved early small-molecule structures by using the fact that the measured intensity is a direct Fourier transform of the density autocorrelation function—the so-called Patterson function in crystallography (43). By looking at all possible interatomic vector arrangements in trial structures, one can find the structure that best fits the experimentally measured Patterson. As the structures get larger and more complex, however, this simple trial-and-error method becomes more difficult owing to the exponential growth in the number of interatomic vectors in three dimensions. Over the years many more powerful phasing methods have been developed, including direct methods (44), isomorphous replacements (45), molecular replacement (46), multiple anomalous dispersion (47, 48), and solvent flattening (49). The use of other experimental measured phase information, such as noncrystallographic symmetry (50, 51), molecular envelope (52) or triplet phases (53, 54), can also be exploited to solve protein crystal structures and is of current research interest.

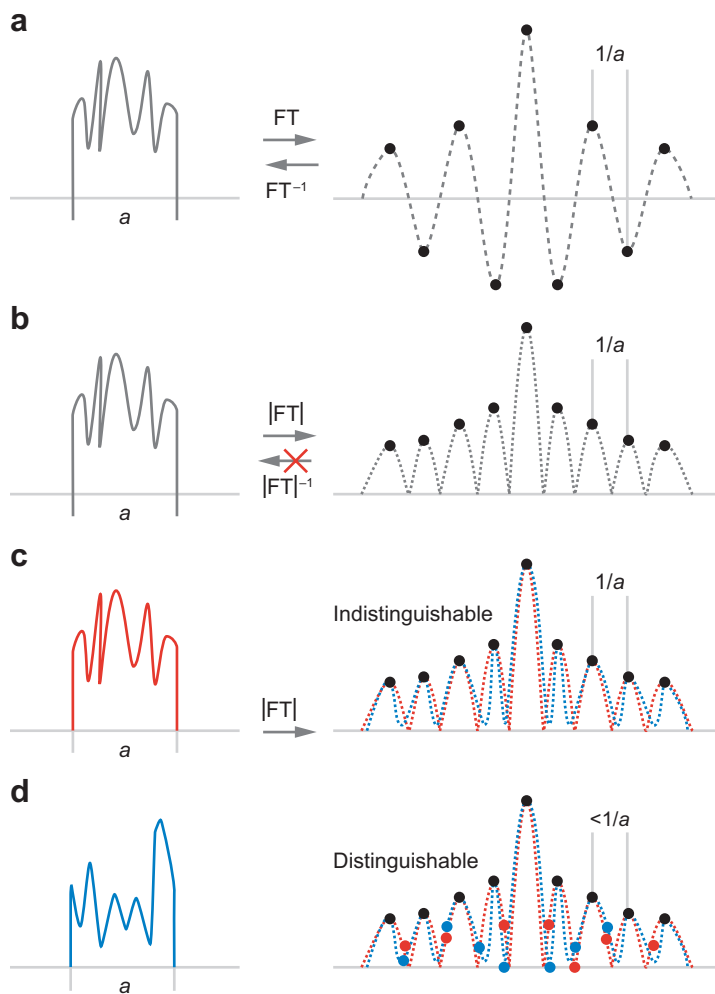
## The Oversampling Method

When the specimen is noncrystalline, the diffraction pattern becomes continuous and weak, in contrast to the sharp Bragg peaks from a crystal. One can solve the phase problem of the continuous diffraction pattern using a different class of phasing techniques called the oversampling method. According to Shannon's (55) sampling theorem, when a function is band limited within  $(0, a)$ , its Fourier transform sampled at the Nyquist interval  $(1/a)$  fully and exactly determines the function itself (**Figure 2a**). When comparing Shannon's sampling with X-ray diffraction from crystals (**Figure 2b**), we can see that the sampling frequency is the same (13). Theoretically, an infinite number of electron density functions can produce the same modulus of the Fourier transform sampled at the Nyquist interval, which is defined as indistinguishable (**Figure 2c**) (6, 9). Based on the argument that the autocorrelation function of any object is twice the size of the object itself, Bates (56) concluded in 1982 that if and only if a diffraction pattern is sampled at a frequency twice finer than the Nyquist interval, phases can be uniquely retrieved from the intensity. In 1998, Miao et al. (7) showed that Bates's conclusion is overly restrictive and proposed a different explanation. They introduced the oversampling ratio ( $\sigma$ ) to characterize the degree of oversampling, where  $\sigma = \sigma_x \sigma_y \sigma_z$  and  $\sigma_x$ ,  $\sigma_y$ , and  $\sigma_z$  represent the sampling frequency divided by the Nyquist interval in the  $x$ ,  $y$ , and  $z$  axis, respectively. When  $\sigma > 2$ , the number of correlated intensity points is more than the number of unknown variables, and the modulus of the Fourier transform can in principle uniquely determine the electron density (7), which is defined as distinguishable (**Figure 2d**). Oversampling a diffraction pattern requires good coherence of the incident waves. The higher the oversampling degree is, the better the required coherence. It is the coherence that causes the correlation of the diffraction intensity and provides the phase information (16). We note that oversampling a diffraction pattern is different from a support constraint. When the diffraction pattern is sampled at a frequency finer than the Nyquist interval but not sufficiently finer, there is a support, but phases are not unique. The unique phases exist only when the sampling frequency is sufficiently finer than the Nyquist interval (i.e.,  $\sigma > 2$ ).

## Iterative Algorithms

Oversampling a diffraction pattern with  $\sigma > 2$  encodes the phases in the diffraction intensity. It is, however, a daunting task to find the unique phases from the number of correlated intensity points (i.e., nonlinear equations). An efficient approach uses global optimization methods such as error reduction (8), hybrid input-output (8), difference map (10), shrink-wrap (11), and Hamiltonian methods (57), all of which are iterated back and forth between real and reciprocal space (58). One approach that shows good convergence and reliable phase retrieval is called the guided hybrid input-output algorithm (35, 38, 59) as illustrated below:

1. The approach starts typically with 16 independent reconstructions on an oversampled X-ray diffraction pattern, in which different random phases are used as initial inputs.



**Figure 2**

(a) A band-limited function and its Fourier transform (FT) sampled at the Nyquist interval (*black dots*). (b) The electron density of a unit cell inside a crystal and its modulus of the FT sampled at Bragg peak frequency at which the crystal lattice effect is ignored. (c) An infinite number of electron density functions can produce the same modulus of the FT sampled at the Nyquist interval (*black dots*). (d) If the modulus of the FT is sampled at a frequency finer than the Nyquist interval (i.e.,  $\sigma > 2$ ), the modulus of the Fourier transform (*the black and red dots versus the black and blue dots*) can in principle uniquely determine the electron density.

2. Each reconstruction is iterated back and forth between real and reciprocal space. For the initial 500 iterations, the electron density outside the support and the negative electron density inside the support are slowly pushed to zero. In reciprocal space, the Fourier modulus remains unchanged and only the phases are updated.

- For the next 500 iterations, a procedure called boundary pushing is adopted, in which the electron density outside the support and the negative electron density inside the support are quickly pushed to zero. This step imposes a stronger constraint than step 2.
- After 1000 iterations, 16 independently reconstructed images are obtained, defined as the zeroth generation. An  $R_F$  is calculated for each image,

$$R_F = \frac{\sum_{k_x, k_y} ||F_{exp}| - \alpha|F_{cal}||}{\sum_{k_x, k_y} |F_{exp}|}, \quad (1)$$

where  $|F_{exp}|$  and  $|F_{cal}|$  represent the experimental and calculated Fourier modulus, respectively;  $k_x$  and  $k_y$  are the coordinates in reciprocal space; and  $\alpha$  is the scaling factor.

- A seed image ( $\rho_{seed}$ ) is chosen that corresponds to the smallest  $R_F$ . The other 15 images ( $\rho_{old}$ ) are aligned to the seed using cross-correlation.
- A set of new images ( $\rho_{new}^i$ ) is calculated by

$$\rho_{new}^i = \sqrt{\rho_{seed} \times \rho_{old}^i} \quad i = 1, 2, \dots, 16, \quad (2)$$

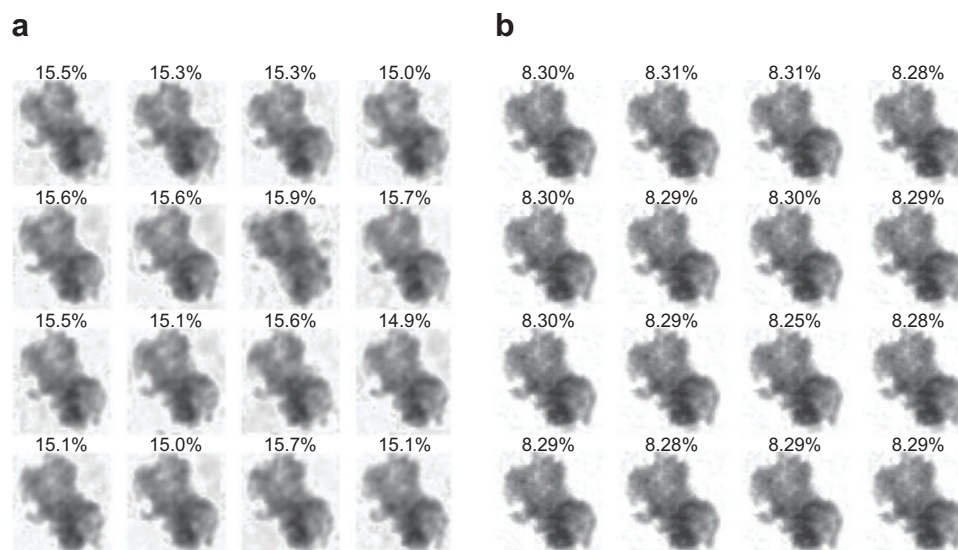
which is used as the initial input for the next generation. Equation 2 merges the best image in the current generation with each of the 16 images, so the favorable gene (i.e., the smallest  $R_F$ ) is passed on to the succeeding generations. Furthermore, density fluctuations in the new image are significantly reduced after the multiplication of the two independent images.

- Steps 1–6 are repeated, and, usually after the eighth generation, the final 16 images become consistent.

To show the good convergence and consistency of the guided hybrid input-output algorithm, we illustrate an example on phasing an oversampled X-ray diffraction pattern from a GaN quantum-dot particle (35). **Figure 3** shows the 16 reconstructed images at the zeroth and eighth generation. The smallest  $R_F$  at the zeroth and eighth generation is 14.9% and 8.25%, respectively. The 16 reconstructed images are virtually identical at the eighth generation, and the five images corresponding to the smallest  $R_F$  are averaged to be the final reconstructed image for the diffraction pattern.

### 3D STRUCTURAL DETERMINATION OF NONCRYSTALLINE MATERIALS

Because X-ray wavelengths are on the order of the size of atoms, and X rays have a longer penetration depth than electrons, scientists have long dreamed of atomic-resolution X-ray microscopes that could visualize the arrangement of atoms in three dimensions. X rays, however, are much more difficult to focus than electrons. By using X-ray optics, the smallest focal spot currently attainable is  $\sim 30$  nm for hard X rays (60) and  $\sim 15$  nm for soft X rays (61). Furthermore, when the focal spot of soft X rays reaches 15 nm, the depth of focus becomes less than  $0.5 \mu\text{m}$  (62), which limits the thickness of the sample under investigation. By avoiding the use of lenses, X-ray diffraction microscopy overcomes the limitations imposed by X-ray optics and has

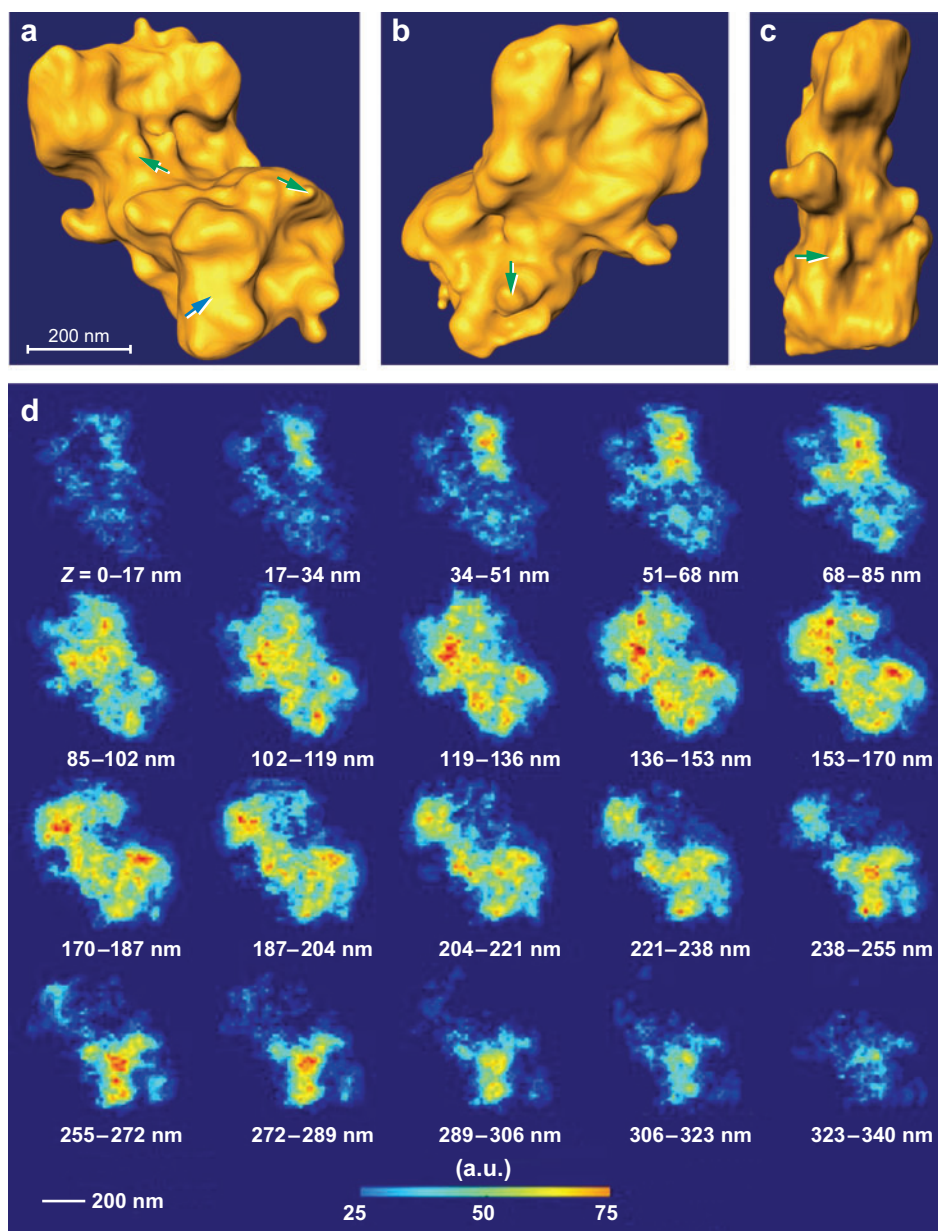


**Figure 3**

Phasing an oversampled X-ray diffraction pattern from a GaN quantum-dot particle by the guided hybrid input-output algorithm. The 16 reconstructed images at the (a) zeroth and (b) eighth generation, where the  $R_F$  value for each image is shown. Figure taken from Reference 35.

been successfully applied to the structural determination of noncrystalline materials such as nanoparticles, nanocrystals, and biological materials (15–39). Currently two versions of X-ray diffraction microscopy are under rapid development. The first is based on forward X-ray diffraction, and the reconstructed images represent the electron density of the sample structure (16, 19, 20, 22, 27, 28, 30, 33–39, 63). The second employs Bragg diffraction from the sample's crystal planes, which has been used not only to determine the shape of a nanocrystal, but also to map out the strain field inside the nanocrystal (5, 15, 23, 32).

To illustrate the unique capability of X-ray diffraction microscopy, we use the 3D structural determination of a GaN quantum-dot nanoparticle as an example (28, 35). The GaN quantum-dot particles were heat treated in a flowing stream of pure  $N_2$  gas (flow rate of  $100 \text{ ml min}^{-1}$ ) at  $900^\circ\text{C}$  for 24 h. The nitrogen atmosphere created an environment with a low partial pressure of oxygen, thus oxidizing the GaN particles at a controllable rate and forming a thin shell of Ga oxide on the GaN core (64). By using a third-generation synchrotron undulator with 5-keV X rays, investigators collected a set of 27 oversampled diffraction patterns from a single GaN quantum-dot nanoparticle with the tilt range of  $-69.4^\circ$  to  $+69.4^\circ$ . The 27 diffraction patterns were directly phased using the guided hybrid input-output algorithm and then inverted to a 3D image. **Figure 4** shows isosurface renderings of the reconstructed 3D image. A distinctive feature of the particle is the platelet-like structure. By examining the 3D surface morphology, one can observe the formation of small islands with varied size on the particle's surface, which results from the surface oxidation of GaN platelets



**Figure 4**

Isosurface rendering of a reconstructed 3D GaN quantum-dot particle, showing (a) the front, (b) back, and (c) side view. A platelet is indicated by a blue arrow in panel a. The formation of small islands (green arrows) on the surface of the particles is clearly visible. (d) The 3D internal structure of the GaN quantum-dot particle. The 3D GaN-Ga<sub>2</sub>O<sub>3</sub> core shell structure is clearly visible, with the low electron density (blue) corresponding to  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> and the high electron density (red) corresponding to the GaN cores. Figure taken from Reference 35.



after the heat treatment. To quantitatively visualize the 3D internal structure, one computationally slices the particle slice by slice, with each corresponding to 17 nm (**Figure 4d**). **Figure 4d** shows that the high-density region, concentrated near the center of the platelets, is surrounded by low density. The low electron density is from the  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> regions of the particle, whereas the high electron density is from the GaN particle. During the GaN surface-oxidation process, small island-like features of  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> formed on the surface of the platelets, which have a lower quality of crystallinity than the GaN cores and give rise to the low electron density. This observation provides direct evidence of the existence of a 3D GaN-Ga<sub>2</sub>O<sub>3</sub> core shell structure in heat-treated GaN platelets.

X-ray diffraction microscopy has emerged as a powerful technique for the 3D imaging and characterization of a wide range of noncrystalline materials, including porous materials, semiconductors, quantum dots and wires, inorganic nanostructures, and biomaterials. Compared with transmission electron or scanning probe microscopy (65, 66), X-ray diffraction microscopy does not require destructive sample preparation and can quantitatively image thick materials in three dimensions. Although the highest resolution achieved to date is  $\sim 7$  nm (67), the ultimate resolution is only limited by the X-ray wavelengths. As more brilliant X-ray sources emerge, such as XFELs that are under rapid development worldwide (68, 69), it is anticipated that X-ray diffraction microscopy will eventually achieve near-atomic resolution in three dimensions.

## STRUCTURE OF WHOLE CELLS

A full and comprehensive understanding of biological processes requires knowledge of the 3D structure of the cell's constituents at resolutions that range from atomic (as in the structure of proteins and nucleic acids) to the somewhat lower-resolution information about the localization, and changes in localization, of these molecules and the molecular assemblies they form (70). With the structural elucidation of the components by structural genomics (71) and other projects, it is necessary to develop resources and approaches to study these molecules' interactions and their dynamic localization in the cell. As informative as the atomic-resolution studies of proteins have proven to be, knowledge of the structure and dynamics of the cell's molecular interaction networks as well as their localization is critical. Recent studies of these protein-protein interaction networks indicate that within the cell most proteins exist and function as components of multiprotein complexes—some stable but many transient and weakly associated. Many of these complexes, and their associated functions, demonstrate tightly coupled spatial and temporal regulation in eukaryotic (72, 73) and prokaryotic cells (74, 75).

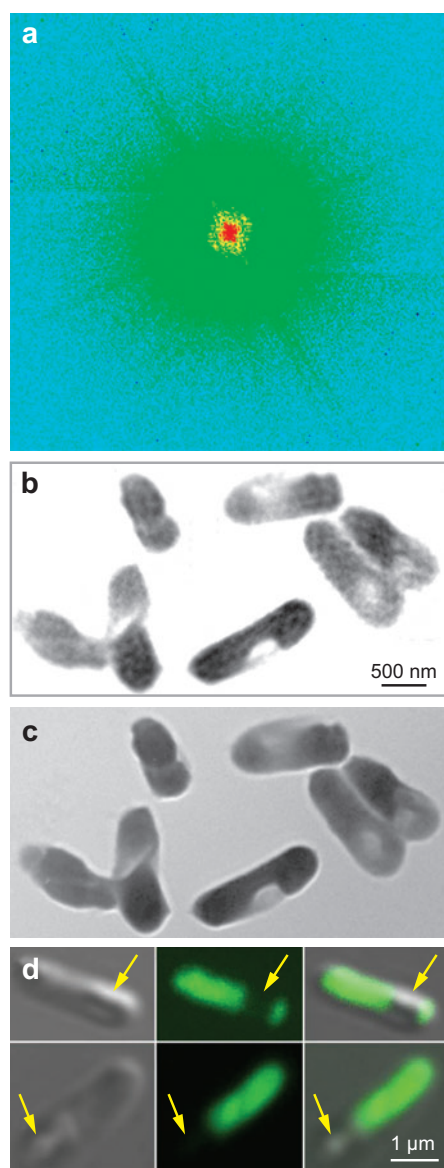
Although light microscopy can routinely study dynamic processes in living cells (76), its resolution is currently limited to  $\sim 200$  nm. In some special cases, better resolutions (up to 20 nm) may be obtained using techniques such as stimulated emission depletion microscopy (77) or photoactivated localization microscopy (78). To achieve considerably higher resolution, one needs much shorter wavelength illumination. Using magnetic lenses, electron microscopy has been applied to the 3D imaging of

thin cellular organelles at a resolution of 3–5 nm (2). The pioneering work on the cryo-electron tomography of cells (2, 79), performed on thin areas in which multiple scattering events are unlikely, has demonstrated clearly the internal complexity and organization of cells. These studies have visualized macromolecular assemblies in the cell around the 5-nm-resolution range. This method of mapping the location of assemblies, however, is limited to samples from either small cells, thin sections of cells, or samples, which can be cryo-sectioned. Even with these restrictions, cryo-electron tomography can visualize large complexes and cytoskeletal architectures in those samples and provide valuable information on their localization.

When comparing light and electron microscopy, one sees a large gap in terms of sample thickness and spatial resolution. X-ray tomography using zone plates for focusing elements can also provide 3D information, currently at ~60 nm for cells (80), with improvements in optics offering the hope for even higher resolution. This technique also has the disadvantage regarding the defocus across the thickness of the sample, as well as the low efficiency of X-ray usage due to the zone plates. Because of its applicability to thick specimens and its high-resolution imaging capability, X-ray diffraction microscopy is an ideal candidate to bridge the gap between light and electron microscopy and to provide quantitative 3D structural information of whole cells at higher resolution.

With the development of X-ray diffraction microscopes (coupled with high-brightness beam lines with coherence areas greater than the sample size), one can investigate thicker samples—whole eukaryotic or prokaryotic cells and multicellular tissues. Here we illustrate two examples of X-ray diffraction imaging of whole cells. The first is the localization of histidine-tagged proteins inside *Escherichia coli* bacteria (22). The *E. coli* bacteria were transformed with a recombinant protein constructed from a pET-23b vector containing a C-terminal tag with six histidines plus the coding sequence for yellow fluorescent protein; this protein has no bacterial function and was used solely as a marker protein. The yellow fluorescent protein tag enabled visualization in a fluorescence microscope. The bacteria were incubated in a 1% solution of  $\text{KMnO}_4$  for 10 min, rinsed, applied as a sparse monolayer to a 150-nm-thick silicon nitride substrate, and air dried.  $\text{KMnO}_4$  acts as a fixative and also reacts to form  $\text{Mn}^{4+}$  ions that bind to the polyhistidine sequences forming a dense precipitate that strongly diffracts X rays.

**Figure 5a** shows an oversampled diffraction pattern recorded from the manganese-tagged *E. coli* bacteria using 5-keV coherent X rays. The radiation dose to the sample was estimated to be  $\sim 8 \times 10^6$  Gy. According to previous experiments (81, 82), this dose would not make any appreciable change in the structure of the sample at this resolution. By using the phase retrieval algorithm, the investigators directly inverted the diffraction pattern to a good-quality image (**Figure 5b**). Based on the power density spectrum, the resolution was measured to be 30 nm. The reconstructed image is in good agreement with the image obtained from transmission X-ray microscopy (**Figure 5c**) (83). The slight difference between the two images is likely caused by the different X-ray wavelengths employed and the different imaging mechanisms. The reconstructed image reveals bacteria with a density pattern that bears a remarkable resemblance to the pattern seen from comparable bacteria examined with



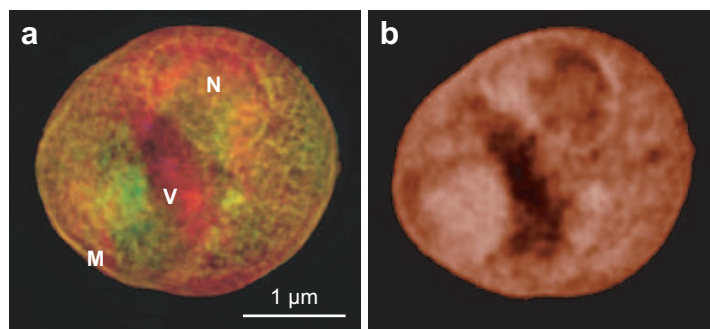
**Figure 5**

(a) Oversampled diffraction pattern from *E. coli* bacteria. (b) The corresponding reconstructed image. The dense regions inside the bacteria are likely the distribution of proteins labeled with  $\text{KMnO}_4$ . The semitransparent regions are devoid of yellow fluorescence proteins. (c) A transmission X-ray microscopy image of the same specimen. (d) Individual bacteria are seen using transmitted light (left column) and fluorescence (middle column). The yellow fluorescence protein (green) is seen throughout most of the bacteria except for one small region in each bacterium that is free of fluorescence (arrows). (Right column) The fluorescent image superimposed on the transmitted light image. Figure taken from Reference 22.

a confocal microscope (**Figure 5d**). The fluorescently labeled protein was distributed throughout the entire bacterium, except for one small region in each bacterium that appears devoid of protein (**Figure 5b**). Similarly, bacteria in the reconstructed image contain dense regions that likely represent the histidine-tagged proteins complexed with manganese and a semitransparent region that is devoid of fluorescent proteins. Although it is not clear what this fluorescent protein-free spot represents, its size and shape are fairly consistent with bacteria seen in both fluorescence and X-ray modalities. Furthermore, the ability to detect this region using fluorescence microscopy on bacteria not yet exposed to X rays precludes the possibility of it being an artifact induced by radiation damage.

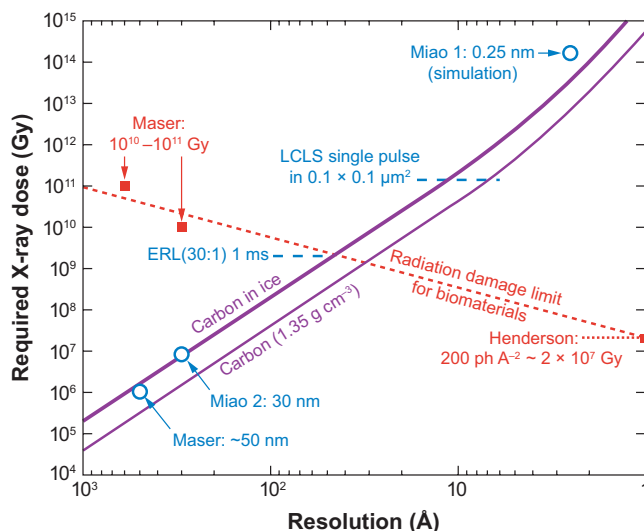
The second example is the X-ray diffraction imaging of a yeast, *Saccharomyces cerevisiae* (27, 30). The cells were plunge frozen in liquid ethane and then dried in a commercial freeze dryer. Oversampled diffraction patterns were collected from a single cell using 750-eV X rays. The diffraction pattern was directly inverted to a high-resolution image by the difference map algorithm. Owing to the strong absorption of the cell at this X-ray energy, the reconstructed image is complex valued with the real and imaginary components corresponding to the scattering and absorption, respectively. **Figure 6a** shows the complex-valued reconstructed image. By using the power spectrum density, the investigators estimated the resolution of the reconstructed image to be 30 nm. **Figure 6b** shows a scanning transmission X-ray microscope image of the same specimen using an X-ray energy of 540 eV (83). Although the two images are in good agreement, the X-ray diffraction microscope image shows a better contrast and a higher resolution than the scanning transmission X-ray microscope image. Furthermore, one can identify some intracellular organelles in **Figure 6a**, such as a nucleus, a storage vacuole, the cell membrane, and the nuclear membrane.

The reconstructed images shown in **Figure 5b** and **Figure 6a** represent 2D projections of 3D objects. To identify the 3D intracellular structure and localize specific



**Figure 6**

(a) X-ray diffraction microscope image of a freeze-dried yeast cell in which N represents a nucleus, V a storage vacuole, and M the cell membrane. (b) Scanning transmission X-ray microscope image of the same cell. The brightness represents the magnitude, and the hue represents the phases. Figure taken from Reference 27.



**Figure 7**

Required X-ray dose at 8 keV to achieve a given spatial resolution for biological samples. A fixed sample volume of  $V = 0.1 \times 0.1 \times 0.1 \mu\text{m}^3$  is assumed. Also plotted are several experimental studies from the literature (Henderson refers to Reference 84, Maser to Reference 83, Miao 1 to Reference 99, and Miao 2 to Reference 22). The radiation limit is shown as the dotted red line connecting Henderson's (84) limit at atomic resolution and microscopy studies against mass loss at low resolutions. Figure taken from Reference 85. ERL, Energy Recovery Linac; LCLS, Linac Coherent Light Source.

multiprotein complexes inside whole cells, one needs the 3D image reconstruction of whole cells at a higher resolution. The resolution of X-ray diffraction microscopy is determined by how far the specimen can diffract, which is ultimately limited by radiation damage to the specimen. Several groups have studied the radiation-damage effect in the X-ray diffraction of biological specimens. At atomic resolution, it is commonly accepted that a dose of  $2 \times 10^7$  Gy would be enough to destroy crystalline orders in protein crystals (84). At lower resolutions, soft X-ray microscopic studies of mass losses in frozen-hydrated cells have shown that a much higher dose of  $\sim 10^{10}$  Gy can be tolerated at liquid nitrogen temperatures (81, 82). From the combination of the empirical radiation-damage data and the theoretical estimates on the required dose to achieve a given spatial resolution (Figure 7), it has been estimated that the resolution of X-ray diffraction microscopy is likely limited to a few nanometers in three dimensions (85, 86).

Future developments that will be critical to this field are further sample-handling methods, brightness and coherence preserving optics, and detectors with small point-spread function and photon-counting capabilities. The preservation of the samples in their closest-to-native state through the use of frozen-hydrated cells requires significant further advances to make this a routine tool for biologists in their investigation into the biology and architecture of the cell.

## OVERCOMING THE RADIATION-DAMAGE BARRIER USING X-RAY FREE ELECTRON LASERS

### The Next Generation Source: X-Ray Free Electron Lasers

Although most X-ray diffraction imaging experiments have been carried out with existing synchrotron light sources, scientists need much higher source brightness than is currently available to extend the methods to smaller samples or to achieve higher spatial resolution. An XFEL is a solution to provide the required source brightness.

Madey (87) invented the free electron laser (FEL) in 1971 as a relativistic electron tube using an open optical resonator. In an FEL, a beam of relativistic electrons (produced by an electron accelerator) passes through a transverse, periodic magnetic field (produced by a magnet called an undulator) and exchanges energy with an electromagnetic radiation field in a resonator. The resonance among the electron beam, the undulator field, and the existing electromagnetic radiation field produces an alignment of electrons with a period of a wavelength, which is sometimes referred to as microbunching. The perfectly microbunched electron beam radiates coherently and amplifies the existing radiation. Therefore, the emission rate for the perfectly bunched beam of electrons is proportional to the square of the number of electrons, whereas the emission rate for a beam of randomly positioned electrons is simply proportional to the number of electrons.

The physical principle governing the operation of an FEL is the same in all wavelength regions. However, because there are no X-ray mirrors that are adequate to construct an X-ray resonator, the XFEL was not developed using Madey's original scheme. Instead, all ongoing XFEL plans are based on the self-amplified spontaneous emission process (88, 89). They employ linear accelerators instead of a storage ring as electron accelerators and use sufficiently long undulators as the FEL amplifier. Together with sufficient beam current, the bunching process can be completed in a single pass along the FEL amplifier.

There are three major XFEL construction projects currently in process in the world. The Linac Coherent Light Source, first proposed by Pellegrini (90), is scheduled to operate at the Stanford Linear Accelerator Center in 2009. The Japanese XFEL is scheduled to be complete in 2011, which will be adjacent to the SPring-8 (a third-generation 8-GeV synchrotron light source) at the RIKEN Harima Institute, Japan. In 2013, the European XFEL is scheduled to be complete at the German Electron Synchrotron research center. Each XFEL is expected to have the following properties, which are appropriate for X-ray diffraction microscopy. First, the radiation energy can be easily tuned by changing either the electron-beam energy or magnetic-field strength. Because the lasing medium cannot be damaged by an extremely high optical field, XFELs can produce high peak power exceeding the gigawatt level. Because the temporal pulse structure of the radiation mimics the pulse structure of the electron beam, electron-beam-handling technologies such as the radiofrequency linear accelerator technology can be used to manipulate and control the XFEL pulse structure. Above all, the most remarkable feature is that XFELs easily achieve the desirable properties associated with conventional lasers, such as a

single transverse mode and high spatial and temporal coherence. With these excellent radiation properties, XFELs are regarded as the next generation of X-ray sources.

### Overcoming the Radiation-Damage Barrier

Perhaps the most exciting idea proposed in the community to overcome the radiation-damage problem for biological specimens is the use of ultrafast XFEL pulses in coherent diffraction experiments to record a coherent diffraction pattern before the macromolecule explodes in an intense X-ray beam (91, 92). Such proposed XFEL experiments would involve a molecular beam capable of providing a stream of randomly oriented macromolecules, and the recording of a diffraction pattern would be synchronized with the arrival of an X-ray pulse onto a macromolecule in the molecular beam. The incident single-pulse intensity is not strong enough to fully record a high-resolution diffraction pattern, and many thousands of identical copies of each pattern (corresponding to a snapshot of a given molecular orientation) would have to be sorted and added to provide statistically significant signals at the atomic resolution. Theoretical modeling has suggested that in order to make this short-pulse diffraction experiment work, the XFEL pulses need to be shorter than a few femtoseconds (93).

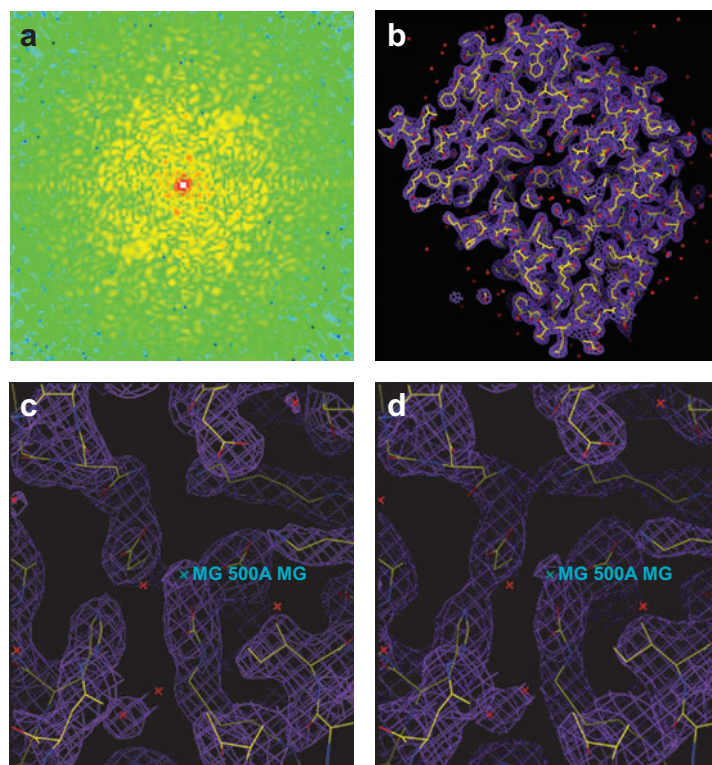
Chapman et al. (31) recently demonstrated experimentally the ultrafast coherent diffraction principle using the FLASH soft X-ray free electron laser in Hamburg, Germany. In that experiment, an intense 25-fs,  $4 \times 10^{13} \text{ W cm}^{-2}$  pulse, containing  $10^{12}$  photons at 32-nm wavelength, produced a coherent diffraction pattern from a nanostructured nonperiodic object, before destroying it into plasma. A novel X-ray camera assured single-photon detection sensitivity by filtering out parasitic scattering and plasma radiation. The reconstructed image, obtained directly from the coherent pattern by phase retrieval through oversampling, shows no measurable damage, and is reconstructed at a reasonable resolution. This successful experiment indicates that significant damage occurs only after the ultrashort 25-fs FEL pulse traverses the specimen. When shorter-wavelength X-ray lasers become available, more experiments will be necessary to determine how high a resolution flash imaging can be applied.

Other experiments at FLASH on multilayer reflectivity measurements (94) have shown significant reduction in reflectivity during the 25-fs pulse duration at higher pulse intensities. This reduction has been attributed to the modification of the optical constants in the multilayer sample by the irradiation of the intense FLASH laser pulse, not the significant atomic movements or disorders in the multilayer caused by the pulse. These initial results are encouraging and have implications for studying nonperiodic molecular structures in biology, or in any other area of science and technology in which structural information with high spatial and temporal resolution is valuable.

### TOWARD IMAGING SINGLE LARGE PROTEIN COMPLEXES

As described in the previous section, theoretical studies have shown that using an extremely bright and ultrashort XFEL pulse, one can collect a 2D diffraction pattern

from a protein molecule before it is destroyed. By using spraying techniques, identical molecules can be selected and injected one by one into an XFEL beam, each generating a 2D diffraction pattern. To assemble a 3D diffraction pattern from these 2D patterns, one needs to determine the orientation of each molecule using one of two methods. The first is to use laser fields to physically align each molecule before the exposure, which has been experimentally demonstrated on small molecules (95). The other is to determine the molecular orientation from the 2D diffraction patterns using the methods developed in cryo-electron microscopy (3, 96). Although either method may result in high noise of the orientation determination, the signal-to-noise ratio can be greatly improved by averaging a large number of molecules at the same orientation and by employing larger protein molecules (e.g., molecular weight  $>100$  kDa) (84). To date, a number of groups have been working on the molecule



**Figure 8**

(a) One section of a simulated 3D diffraction pattern processed from  $10^6$  identical copies of the rubisco molecules with Poisson noise added. The edge of the diffraction pattern corresponds to  $2.5\text{-}\text{\AA}$  resolution. The white square at the center corresponds to the missing data owing to a beam stop. (b) Stereoview of the 3D electron density map of the rubisco molecule (contoured at two sigma) reconstructed from panel a on which the correct atomic model is superimposed. (c) The corresponding active site. (d) The active site reconstructed from  $3 \times 10^5$  identical rubisco molecules with Poisson noise added. Figure taken from Reference 97.



injection techniques and the orientation-determination algorithms, obtaining some encouraging results.

After the determination of the molecular orientation, a 3D diffraction pattern can be assembled from the 2D diffraction patterns and then phased to obtain the 3D structure of the molecule. To demonstrate the potential of imaging single large protein molecules using coherent X rays, we give an example on phasing a simulated 3D diffraction pattern from rubisco molecules (97). XFEL pulses were simulated with a wavelength of 1.5 Å, pulse flux of  $2 \times 10^{12}$  photons, a pulse length of 10 fs, and a focal spot of 0.1- $\mu\text{m}$  diameter. Each pulse was synchronized to hit a rubisco molecule and generated a 2D diffraction pattern in which atomic coordinates of the molecule were obtained from the Protein Data Bank. In this simulation, it is assumed that the orientation of each molecule has been determined by the methods described above. By using  $10^6$  2D diffraction patterns, investigators assembled a 3D diffraction pattern with a size of  $160 \times 160 \times 160$  voxels and a resolution of 2.5 Å. To simulate noise, they added Poisson statistical noise to the diffraction pattern. **Figure 8a** shows a section of the 3D diffraction pattern. By using the oversampling and iterative phasing algorithm, they reconstructed the 3D electron density of rubisco from the 3D diffraction pattern. **Figure 8b,c** shows a stereoview of the reconstructed 3D electron density map and the active site, onto which the same atomic model is superimposed. The reconstructed electron density map is almost identical to the true one except for some small differences. To increase the Poisson noise, researchers processed a 3D diffraction pattern from  $3 \times 10^5$  identical copies of the rubisco molecules and then directly phased it to obtain a 3D electron density map. **Figure 8d** shows a stereoview of the reconstructed active site. Compared with **Figure 8c**, the quality of the reconstructed electron density map deteriorates somewhat as some of the electron density positions in **Figure 8d** shift a little bit relative to that in **Figure 8c**.

#### SUMMARY POINTS

1. When a diffraction pattern is sampled at a frequency finer than the Nyquist interval so that the oversampling ratio ( $\sigma$ ) is larger than 2, the phase information is usually encoded in the diffraction intensity and can be directly recovered using an iterative algorithm.
2. By using the oversampling phasing technique, investigators have successfully extended X-ray crystallography to allow the structural determination of noncrystalline specimens. By avoiding the use of lenses, this methodology is also called lensless imaging (using computation as lenses) or X-ray diffraction microscopy.
3. X-ray diffraction microscopy has been applied to quantitative 3D imaging of noncrystalline materials. The highest resolution achieved thus far is approximately 7 nm, which is mainly limited by the coherent X-ray flux. With

the prospects of more brilliant X-ray sources such as XFELs (68, 69) and energy recovery linacs (98), we anticipate that X-ray diffraction microscopy will be able to image the 3D structure of noncrystalline materials at the near-atomic level.

4. Because X rays have a longer penetration depth than electrons, X-ray diffraction microscopy has been applied to imaging whole *E. coli* and yeast cells at a resolution of 30 nm. By using cryogenic technologies, one should be able to image whole frozen-hydrated cells at a resolution of 10 nm or better in three dimensions, which will allow the localization of specific multiprotein complexes inside the cells.
5. Theoretical studies have shown that, by using extremely intense and ultrashort XFEL pulses, one can record a diffraction pattern from a single biomolecule before it is destroyed. The combination of X-ray diffraction microscopy and XFEL may thus open a new horizon of imaging single large protein molecules without the need of crystallization.
6. The principle of X-ray diffraction microscopy has also been successfully applied to electrons (17, 24) and tabletop high-harmonic soft X-ray sources (99). The tabletop soft X-ray diffraction microscopy is especially attractive for its applications in materials science, nanoscience, and biology.

## DISCLOSURE STATEMENT

The authors are not aware of any biases that might be perceived as affecting the objectivity of this review.

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14. First experimental demonstration of extending X-ray crystallography to the imaging of noncrystalline specimens.

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16. Reports the first experimental demonstration of 3D X-ray diffraction microscopy.

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21. Proposes a method to uniquely retrieve the phases from oversampled diffraction patterns by using X-ray fields with phase curvature.

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22. Describes the first experiment recording and reconstruction of the diffraction pattern from a biological specimen (i.e., *E. coli* bacteria) at 30-nm resolution using coherent X rays.

27. Uses X-ray diffraction microscopy to image the complex valued exit wave of an intact and unstained yeast cell and proposes a technique to determine the reconstructed resolution.

31. First experimental demonstration that the diffraction pattern of a noncrystalline specimen can be recorded before it is destroyed by a soft XFEL pulse.

32. Reports a novel experiment of revealing the 3D evolution of a deformation field inside a lead nanocrystal by inverting the coherent X-ray diffraction pattern.

37. Reports a novel X-ray diffraction imaging experiment for extended objects, based on the combination of ptychography with an iterative phase-retrieval algorithm.

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91. Using computer simulations, shows that biomolecules can withstand an X-ray intensity of  $\sim 3.8 \times 10^6$  photons  $\text{\AA}^{-2}$  within approximately 10 fs with minimal structural changes.

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